

# **THE DEVELOPMENT OF THE X-RAY RIETVELD METHOD**

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## **ABSTRACT**

The Rietveld method was first developed by Rietveld to extract structural parameters from neutron diffraction patterns. This method, first published in 1967 and 1969, saw limited application during the next decade. It was not until the technique was adapted to x-ray patterns and vigorously publicized to the community that the technique matured to the robust procedure we know today. The second author will review Professor Young's critical role in the development and wide acceptance of this technique and then Prof. Young will be given an opportunity for rebuttal.